



<p style="text-align: center;">Searched</p> 	<p>Application/Control No.</p> <p>10655564</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>DUMITRAS ET AL.</p>
	<p>Examiner</p> <p>Findley, Christopher</p>	<p>Art Unit</p> <p>2635</p>

Class	SubClass	Date	Examiner
348	152	8/28/2006	Christopher Findley
348	169	8/24/2006	Christopher Findley
348	699	8/28/2006	Christopher Findley
348	700	8/22/2006	Christopher Findley
375	240.16	8/28/2006	Christopher Findley
U.S. Patent and Trademark Office			Part of Paper No.: 20060905

Search Notes 	Application/Control No. 10655564	Applicant(s)/Patent Under Reexamination DUMITRAS ET AL.
	Examiner Findley, Christopher	Art Unit 2635

Notes	Date	Examiner
Consulted Lin Ye regarding subclasses to search (he recommended 348/152 and 348/169)	8/24/2006	Christopher Findley
Consulted Vu Le regarding subclasses to search (he recommended 348/699 and 375/240.16)	8/28/2006	Christopher Findley
Searched IEEE Xplor and SPIE Digital Library	9/6/2006	Christopher Findley
Searched SPIE Digital Library	9/7/2006	Christopher Findley
Consulted Vu Le regarding Chang reference and coordinate systems	9/11/2006	Christopher Findley
U.S. Patent and Trademark Office		Part of Paper No.: 20060905